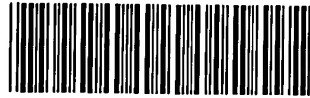


**Search Notes**

Application/Control No.

10/665,204

Examiner

A. Sefer

Applicant(s)/Patent under  
Reexamination

WANG ET AL.

Art Unit

2826

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, US-PG-Pub, Derwent, EPO & JPO)	11/7/2005	AS
257/53,101-103,431-432 (text search)	11/7/2005	AS